

Interactive comment on “Biases caused by the instrument bandwidth and beam width on simulated brightness temperature measurements from scanning microwave radiometers” by V. Meunier et al.

V. Meunier et al.

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Dear Reviewer,

The response to your comments and concerns is found in the attached PDF file.

Cheers, Veronique Meunier

C4014

Please also note the supplement to this comment:
<http://www.atmos-meas-tech-discuss.net/5/C4014/2013/amtd-5-C4014-2013-supplement.pdf>

Interactive comment on Atmos. Meas. Tech. Discuss., 5, 8085, 2012.

C4015